

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination O'NEIL ET AL.	
		Examiner Rodney G. McDonald	Art Unit 1753	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,364,956	04-2002	Wang et al.	118/726
*	C	US-5,773,162	06-1998	Surampudi et al.	429/39
*	D	US-5,395,704	03-1995	Barnett et al.	429/30
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.